

## **Notice of References Cited**

_	Application/Control No.	Applicant(s)/Pater	nt Under
	09/669,556	Reexamination SIMMEN, DAVID E.	
	Examiner	Art Unit	
	Cindy Nguyen	2171	Page 1 of 1

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5991754	11-1999	Raitto et al.	707/2
	В	US-5761653	06-1998	Schiefer et al.	707/2
	C	US-			
	D	US-			
	Е	US-			
	F	US-			
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